

Large anisotropic Fe orbital moments in perpendicularly magnetized Co₂FeAl Heusler alloy thin films revealed by angular-dependent x-ray magnetic circular dichroism

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1 Introduction

MgO-based magnetic tunnel junctions have been developed by exploiting the strong perpendicular magnetic anisotropy (PMA) at the interfaces between MgO and CoFeB transition metal alloys, measuring 2.1×10^5 J/m³ [1], which is comparable to PMA in Co/Pt multilayers. Co-based Heusler alloys Co₂YZ (*Y*: transition metal; *Z*: main group element) have attracted much attention owing to their excellent properties that give rise to high spin polarization. In particular, Co₂FeAl is a promising alloy owing to its low magnetic damping constant at room temperature (RT) and its better lattice matching with MgO as well as a high spin polarization. Recently, Heusler alloys were used to discover PMA in Co₂FeAl thin layers sharing an interface with MgO, with a lattice mismatch of 3.4% [2]. However, the physical origin of PMA at the interface of Co₂FeAl/MgO remains elusive. Clarifying the mechanism of PMA in Co₂FeAl may help design materials with high spin polarization and PMA to be used in future high performance spintronics applications. Here, we report the origin of PMA in Co₂FeAl/MgO interface structures, revealed by the X-ray magnetic circular dichroism (XMCD) technique with element specific orbital magnetic moments.

2 Experiment

Samples were fabricated using the magnetron sputtering method. The films were deposited on MgO (001) substrates. Thin Co₂FeAl samples of 0.8, 2, and 10 nm layer thicknesses with a 2 nm thick MgO layer were deposited at RT. Using the vibrating sample magnetometer (VSM), we confirmed that 0.8 nm thick Co₂FeAl has perpendicular magnetization at RT, while 2 and 10 nm thick Co₂FeAl samples are characterized by in-plane magnetization, as previously reported [2].

The XMCD was performed at BL-7A (Research Centre for Spectrochemistry, The University of Tokyo). A magnetic field of 1 T was applied along the incident polarized soft x-ray. The total electron yield mode was adopted. All measurements were carried out at RT. Samples were rotated from the surface normal to 60°, defined as normal incidence (NI) and grazing incidence (GI), respectively.

3 Results and Discussion

Figure 1 shows the x-ray absorption spectra of Fe and Co *L*_{2,3} edges in Co₂FeAl/MgO layers of different thicknesses. Clear metallic peaks are observed, which confirm that there is no mixing of oxygen atoms in the thin Co₂FeAl layer. For a 0.8 nm thick Co₂FeAl sample,

the asymmetry between the *L*₂ and *L*₃ edges is slightly enhanced in Fe *L* edges, resulting in large residuals for the integrated XMCD intensities of *L*_{2,3} edges. On the other hand, the Co *L*_{2,3} edge XMCD yields almost the same results in both NI and GI geometries. Orbital and spin magnetic moments are deduced separately for Fe and Co 3d electrons using the magneto-optical sum rules. We found that PMA is determined mainly by the contribution of Fe atoms with the large orbital magnetic moments, which are enhanced at the interface between Co₂FeAl and MgO [3].

According to the first principles calculations for the Fe/MgO and Co/MgO interfaces, the Fe-O bonding induces PMA that is stronger as compared to the case of the Co/MgO [4]. Therefore, we conclude that, for a Co₂FeAl, a FeAl layer that shares an interface with MgO, with hybridization between Fe 3*d*₂₂ and O 2*p* orbitals, is more energetically stabilized as compared to the Co layer sharing an interface with MgO.

References

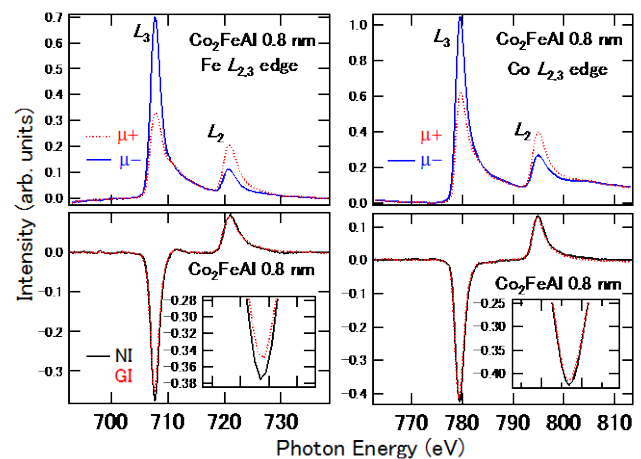


Fig. 1: X-ray absorption spectra and angular-dependent XMCD of the 0.8 nm thick Co₂FeAl / MgO for Fe and Co *L* edges. Inset shows the expanded view around the *L*₃ edges.

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